

Search Notes

Application/Control No.

10/642,790

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

MURAKAMI, TAKEHIKO

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	1		
15	3		
101	423		
101	424	8/20/2005	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, OCR, DERWENT, EPO, JPO	8/20/2005	RC
Inventor name search	8/20/2005	RC